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| Notice of References Cited | Application/Control No. 09/784,352 | Applicant(s)/Patent Under Reexamination HEUER, JOERG | |
| | Examiner Chongshan Chen | Art Unit 2162 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| | A | US-6,233,578 | 05-2001 | Machihara et al. | 707/10 |
| | B | US-6,345,269 | 02-2002 | Kappenberger et al. | 707/3 |
| | C | US-6,397,225 | 05-2002 | Brown et al. | 707/104.1 |
| | D | US-2003/0208473 | 11-2003 | Lennon, Alison Joan | 707/3 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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